**Product data sheet** 

## 1. General description

Planar passivated high commutation three quadrant triac in a TO220F "full pack" plastic package. This triac is intended for use in motor control circuits where very high blocking voltage can occur. Rated junction temperature ( $T_{j(max)}$  = 150 °C) without the aid of a snubber. It is used in applications where "high junction operating temperature capability" is required.

### 2. Features and benefits

- High junction operating temperature capability (T<sub>i(max)</sub> = 150 °C)
- Full cycle AC conduction
- Over-voltage withstand capability to IEC 61000-4-5
- · Pin compatible with standard triacs
- Planar passivated for voltage ruggedness and reliability
- · Protective self turn-on capability for high energy transients
- · Triggering in three quadrants only
- Very high immunity to IEC 61000-4-4 fast transient
- · Package meets UL94V0 flammability requirement
- Package is RoHS compliant
- · Package meets UL1557 isolation test requirement rated at 2500V RMS

## 3. Applications

- · AC fan, pump and compressor controls
- · Highly inductive, resistive and safety loads
- · Large and small appliances (White Goods)
- · Reversing induction motor controls e.g. vertical axis washing machines
- Applications subject to high temperature (T<sub>i(max)</sub> = 150 °C)

#### 4. Quick reference data

#### Table 1. Quick reference data

| Symbol              | Parameter                                | Conditions   | Min | Тур | Max | Unit |
|---------------------|--|--|-----|-----|-----|------|
| $V_{DRM}$           | repetitive peak off-state voltage        |  | -   | -   | 800 | V    |
| I <sub>T(RMS)</sub> | RMS on-state current                     | full sine wave; T <sub>h</sub> ≤ 103°C;<br>Fig.1; Fig. 2; Fig. 3   | -   | -   | 8   | A    |
| I <sub>TSM</sub>    | non-repetitive peak on-<br>state current | full sine wave; T <sub>j(init)</sub> = 25 °C; t <sub>p</sub> =20ms;<br>Fig. 4; Fig. 5                            | -   | -   | 80  | А    |
|                     |  | full sine wave; $T_{j(init)} = 25 \text{ °C}$ ; $t_p = 16.7 \text{ms}$   | -   | -   | 88  | Α    |
| T <sub>j</sub>      | junction temperature                     |  | -   | -   | 150 | °C   |
| Static ch           | aracteristics                            |  |     |     |     |      |
| I <sub>GT</sub>     | gate trigger current                     | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G+;$<br>$T_j = 25 \text{ °C; } Fig. 7$                          | -   | -   | 35  | mA   |
|                     |  | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + \text{ G-;} $ $T_j = 25 \text{ °C; } \underline{\text{Fig. 7}}$ | -   | -   | 35  | mA   |

| Symbol                | Parameter                             | Conditions  | Min | Тур  | Max | Unit |
|-----------------------|---------------------------------------|---|-----|------|-----|------|
|                       |                                       | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; \text{ T2- G-};$<br>$T_j = 25 ^{\circ}\text{C}; \text{ Fig. 7}$   | -   | -    | 35  | mA   |
| I <sub>H</sub>        | holding current                       | V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>  | -   | -    | 40  | mA   |
| V <sub>T</sub>        | on-state voltage                      | I <sub>T</sub> = 10 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>   | -   | 1.25 | 1.6 | V    |
| Dynamic               | characteristics                       |   |     |      |     |      |
| dV <sub>D</sub> /dt   | rate of rise of off-state voltage     | $V_{DM}$ = 536 V; $T_j$ = 125 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit  | 200 | -    | -   | V/µs |
|                       |                                       | $V_{DM}$ = 536 V; $T_j$ = 150 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit  | 100 | -    | -   | V/µs |
| dI <sub>com</sub> /dt | rate of change of commutating current | $V_{DM} = 400 \text{ V}; T_j = 150 \text{ °C}; I_{T(RMS)} = 8 \text{ A};$<br>$dV_{com}/dt = 20 \text{ V/}\mu\text{s}; \text{ (snubberless condition)}; gate open circuit$ | 1   | -    | -   | A/ms |

# 5. Pinning information

Table 2 Pinning information

| Pin | Symbol | Description             | Simplified outline | Graphic symbol |
|-----|--------|-------------------------|--------------------|----------------|
| 1   | T1     | main terminal 1         | 000                | <u>.</u>       |
| 2   | T2     | main terminal 2         |                    | T2—T1          |
| 3   | G      | gate                    |                    | sym051         |
| mb  | n.c.   | mounting base; isolated |                    |                |

# 6. Ordering information

Table 3 Ordering information

| Table 5. Ordering information |         |                       |         |               |         |             |  |  |
|-------------------------------|---------|-----------------------|---------|---------------|---------|-------------|--|--|
| Type number                   | Package | Orderable part number | Packing | Small packing | Package | Package     |  |  |
|                               | Name    |                       | method  | quantity      | version | issue date  |  |  |
| BTA208X-800CT                 | TO220F  | BTA208X-800CTQ        | Tube    | 50            | TO220FE | 25-Sep-2020 |  |  |

# 7. Marking

### **Table 4. Marking codes**

| Type number   | Marking codes    |
|---------------|------------------|
| BTA208X-800CT | BTA208X<br>800CT |

# 8. Limiting values

### **Table 5. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol              | Parameter                                | Conditions   | Min | Max | Unit             |
|---------------------|--|--|-----|-----|------------------|
| $V_{DRM}$           | repetitive peak off-state voltage        |  | -   | 800 | V                |
| I <sub>T(RMS)</sub> | RMS on-state current                     | full sine wave; $T_{mb} \le 103^{\circ}C$ ;<br><u>Fig. 1</u> ; <u>Fig. 2</u> ; <u>Fig. 3</u> | -   | 8   | А                |
| I <sub>TSM</sub>    | non-repetitive peak on-<br>state current | full sine wave; $T_{j(init)}$ = 25 °C; $t_p$ = 20 ms;<br>Fig. 4; Fig. 5                      | -   | 80  | А                |
|                     |  | full sine wave; $T_{j(init)}$ = 25 °C; $t_p$ = 16.7 ms                                       | -   | 88  | А                |
| l <sup>2</sup> t    | I <sup>2</sup> t for fusing              | t <sub>P</sub> = 10 ms; sine wave pulse  | -   | 32  | A <sup>2</sup> s |
| dl <sub>⊤</sub> /dt | rate of rise of on-state current         | I <sub>G</sub> = 70 mA   | -   | 150 | A/µs             |
| I <sub>GM</sub>     | peak gate current                        |  | -   | 2   | А                |
| $P_{GM}$            | peak gate power                          |  | -   | 5   | W                |
| $P_{G(AV)}$         | average gate power                       | over any 20 ms period  | -   | 0.5 | W                |
| T <sub>stg</sub>    | storage temperature                      |  | -40 | 150 | °C               |
| T <sub>j</sub>      | junction temperature                     |  | -   | 150 | °C               |

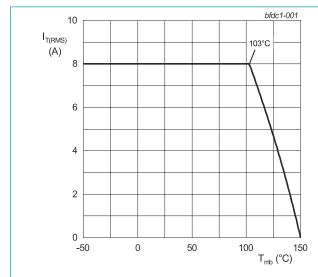
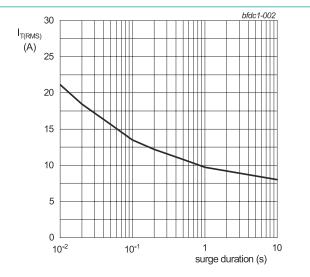
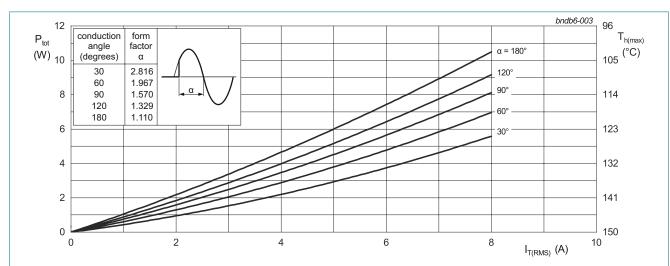


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values



 $f = 50 \text{ Hz}; T_h = 103^{\circ}\text{C}$ 

Fig. 2. RMS on-state current as a function of surge duration; maximum values



a = form factor =  $I_{T(RMS)} / I_{T(AV)}$ 

 $\alpha$  = conduction angle

Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

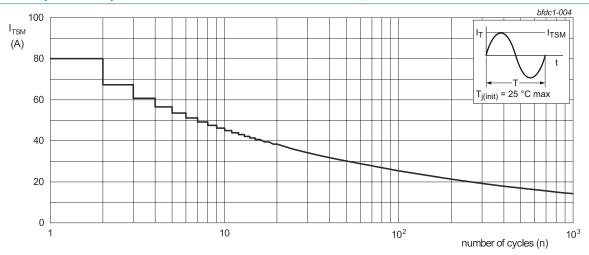
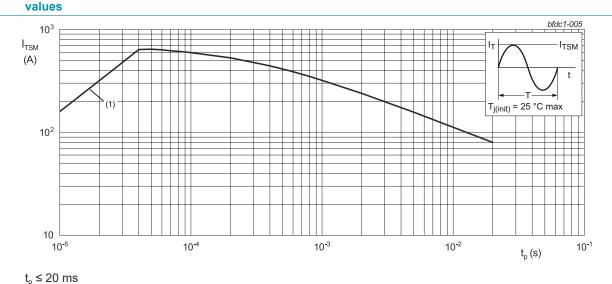


Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum



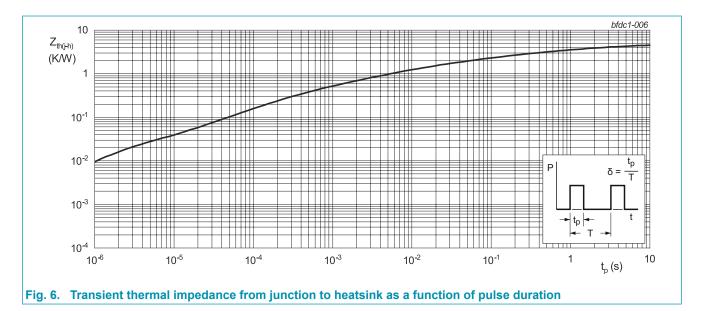
 $(1) dI_{T}/dt limit$ 

Fig. 5. Non-repetitive peak on-state current as a function of pulse duration; maximum values

### 9. Thermal characteristics

**Table 6. Thermal characteristics** 

| Symbol               | Parameter  | Conditions         | Min | Тур | Max | Unit |
|----------------------|--|--------------------|-----|-----|-----|------|
| R <sub>th(j-h)</sub> | thermal resistance<br>from junction to<br>heatsink | full cycle; Fig. 6 | -   | -   | 4.5 | K/W  |
| R <sub>th(j-a)</sub> | thermal resistance<br>from junction to<br>ambient  | in free air        | -   | 60  | -   | K/W  |



### 10. Isolation characteristics

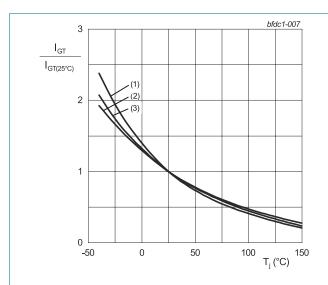
**Table 7. Isolation Characteristics** 

| Symbol                 | Parameter             | Conditions   | Min | Тур | Max  | Unit |
|------------------------|-----------------------|--|-----|-----|------|------|
| V <sub>isol(RMS)</sub> | RMS isolation voltage | from all terminals to external heatsink; sinusoidal waveform; clean and dust free; 50 Hz $\leq$ f $\leq$ 60 Hz; RH $\leq$ 65 %; $T_{mb}$ = 25 °C | -   | -   | 2500 | V    |
| C <sub>isol</sub>      | isolation capacitance | from main terminal 2 to external heatsink; f = 1 MHz; $T_{mb}$ = 25 °C   | -   | 10  | -    | pF   |

## 11. Characteristics

**Table 8. Characteristics** 

| Symbol                  | Parameter                             | Conditions  | Min  | Тур  | Max | Unit |
|-------------------------|---------------------------------------|---|------|------|-----|------|
| Static ch               | aracteristics                         |   |      |      |     |      |
| I <sub>GT</sub>         | gate trigger current                  | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G+; $<br>$T_j = 25 \text{ °C}; Fig. 7$                                      | -    | -    | 35  | mA   |
|                         |                                       | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-;$<br>$T_j = 25 \text{ °C; } Fig. 7$                                   | -    | -    | 35  | mA   |
|                         |                                       | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2- G-;}$<br>$T_j = 25 \text{ °C; } Fig. 7$                                     | -    | -    | 35  | mA   |
| IL                      | latching current                      | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ \text{ G+};$<br>$T_j = 25 \text{ °C}; Fig. 8$                               | -    | -    | 50  | mA   |
|                         |                                       | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ \text{ G-};$<br>$T_j = 25 \text{ °C}; Fig. 8$                               | -    | -    | 70  | mA   |
|                         |                                       | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2- \text{ G-};$<br>$T_j = 25 ^{\circ}\text{C}; \text{ Fig. 8}$                 | -    | -    | 50  | mA   |
| I <sub>H</sub>          | holding current                       | V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>  | -    | -    | 40  | mA   |
| V <sub>T</sub>          | on-state voltage                      | I <sub>T</sub> = 10A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>  | -    | 1.25 | 1.6 | V    |
| V <sub>GT</sub> gate tr | gate trigger voltage                  | V <sub>D</sub> = 12 V; I <sub>T</sub> = 0.1 A;T <sub>j</sub> = 25 °C<br>Fig. 11   | -    | 0.7  | 1   | V    |
|                         |                                       | $V_D = 400V; I_T = 0.1 A; T_j = 150 °C$   | 0.25 | 0.4  | -   | V    |
| I <sub>D</sub>          | off-state current                     | V <sub>D</sub> = 800 V; T <sub>j</sub> = 25 °C  | -    | -    | 10  | μA   |
|                         |                                       | V <sub>D</sub> = 800 V; T <sub>j</sub> = 150 °C   | -    | 0.3  | 2   | mA   |
| Dynamic                 | characteristics                       |   |      |      |     |      |
| dV <sub>D</sub> /dt     | rate of rise of off-state voltage     | $V_{DM}$ = 536V; $T_j$ = 125 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit                 | 200  | -    | -   | V/µs |
|                         |                                       | $V_{DM}$ = 536V; $T_j$ = 150 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit                 | 100  | -    | -   | V/µs |
| dI <sub>com</sub> /dt   | rate of change of commutating current | $V_{DM}$ = 400 V; $T_j$ = 150 °C; $I_{T(RMS)}$ = 8 A; $dV_{com}/dt$ = 20 V/µs; (snubberless condition); gate open circuit | 1    | -    | -   | A/ms |
|                         |                                       | $V_{DM}$ = 400 V; $T_j$ = 150 °C; $I_{T(RMS)}$ = 8 A; $dV_{com}/dt$ = 10 V/ $\mu$ s; gate open circuit                    | 1.5  | -    | -   | A/ms |
|                         |                                       | $V_{DM}$ = 400 V; $T_j$ = 150 °C; $I_{T(RMS)}$ = 8 A; $dV_{com}/dt$ = 1 V/µs; gate open circuit                           | 3    | -    | -   | A/ms |



- (1) T2- G-
- (2) T2+ G-
- (3) T2+ G+

Fig. 7. Normalized gate trigger current as a function of junction temperature

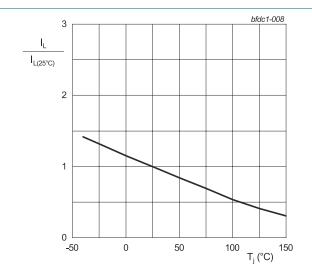


Fig. 8. Normalized latching current as a function of junction temperature

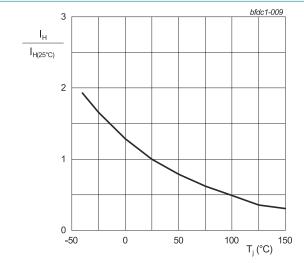
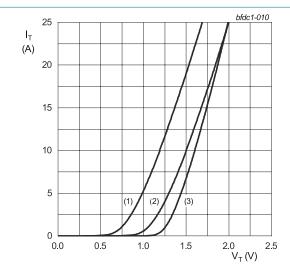


Fig. 9. Normalized holding current as a function of junction temperature



 $V_o = 1.125 \text{ V}; R_s = 0.0373\Omega$ 

(1) T<sub>i</sub> = 150 °C; typical values

(2) T<sub>i</sub> = 150 °C; maximum values

(3)  $T_i = 25$  °C; maximum values

Fig. 10. On-state current as a function of on-state voltage

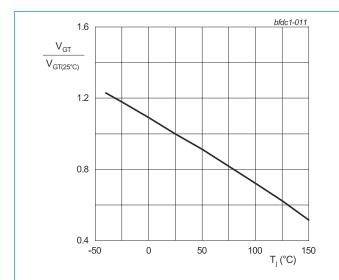


Fig. 11. Normalized gate trigger voltage as a function of junction temperature

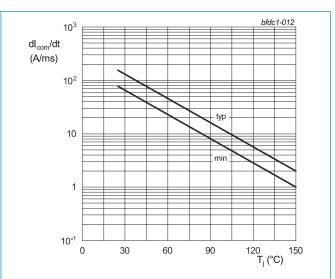
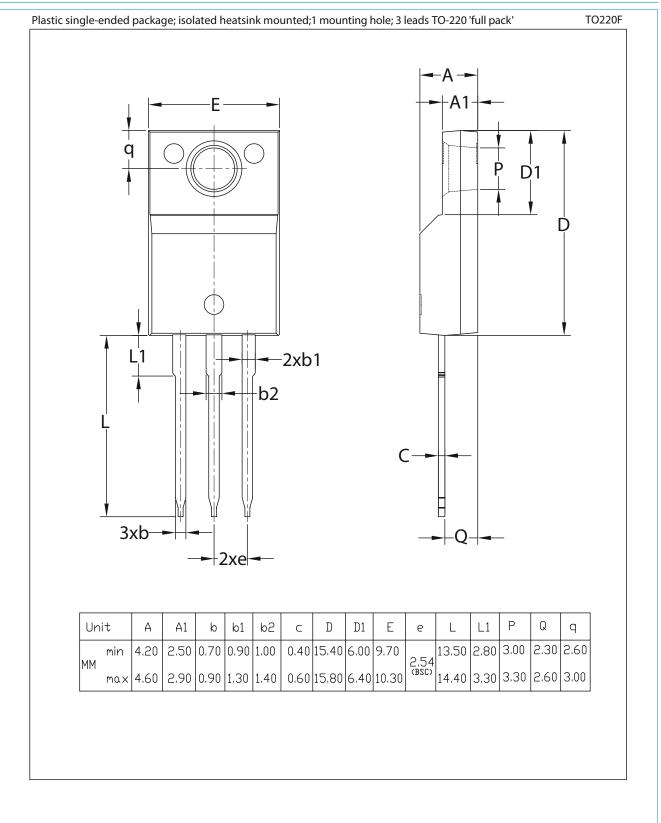


Fig. 12. Rate of change of commutating current as a function of junction temperature; typical and minimum values

# 12. Package outline



## 13. Legal information

#### Data sheet status

| Document status [1][2]               | Product status [3] | Definition  |
|--------------------------------------|--------------------|---|
| Objective<br>[short] data<br>sheet   | Development        | This document contains data from the objective specification for product development. |
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For more information, please visit: http://www.ween-semi.com
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